

<b>STN</b>	<b>Integrované obvody</b> <b>Meranie elektromagnetického vyžarovania</b> <b>Časť 1: Všeobecné podmienky a definície</b>	<b>STN</b> <b>EN IEC 61967-1</b>  35 8796
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Integrated circuits - Measurement of electromagnetic emissions - Part 1: General conditions and definitions

Táto norma obsahuje anglickú verziu európskej normy.  
This standard includes the English version of the European Standard.

Táto norma bola oznámená vo Vestníku ÚNMS SR č. 05/19

Obsahuje: EN IEC 61967-1:2019, IEC 61967-1:2018

Oznámením tejto normy sa od 16.01.2022 ruší  
STN EN 61967-1 (35 8796) z novembra 2002

**128689**

EUROPEAN STANDARD

**EN IEC 61967-1**

NORME EUROPÉENNE

EUROPÄISCHE NORM

February 2019

ICS 31.200

Supersedes EN 61967-1:2002

English Version

**Integrated circuits - Measurement of electromagnetic emissions -  
Part 1: General conditions and definitions  
(IEC 61967-1:2018)**

Circuits intégrés - Mesure des émissions  
électromagnétiques - Partie 1: Conditions générales et  
définitions  
(IEC 61967-1:2018)

Integrierte Schaltungen - Messung von  
elektromagnetischen Aussendungen - Teil 1: Allgemeine  
Bedingungen und Definitionen  
(IEC 61967-1:2018)

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European Committee for Electrotechnical Standardization  
Comité Européen de Normalisation Electrotechnique  
Europäisches Komitee für Elektrotechnische Normung

**CEN-CENELEC Management Centre: Rue de la Science 23, B-1040 Brussels**

**EN IEC 61967-1:2019 (E)****European foreword**

The text of document 47A/1062/FDIS, future edition 2 of IEC 61967-1, prepared by SC 47A "Integrated circuits" of IEC/TC 47 "Semiconductor devices" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN IEC 61967-1:2019.

The following dates are fixed:

- latest date by which the document has to be implemented at national level by publication of an identical national standard or by endorsement (dop) 2019-10-16
- latest date by which the national standards conflicting with the document have to be withdrawn (dow) 2022-01-16

This document supersedes EN 61967-1:2002.

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In the official version, for Bibliography, the following notes have to be added for the standards indicated:

IEC 61967-2	NOTE	Harmonized as EN 61967-2
IEC 61967-4	NOTE	Harmonized as EN 61967-4
IEC 61967-5	NOTE	Harmonized as EN 61967-5
IEC 61967-6	NOTE	Harmonized as EN 61967-6
IEC 61967-8	NOTE	Harmonized as EN 61967-8
IEC 62132-1	NOTE	Harmonized as EN 62132-1
CISPR 25:2008	NOTE	Harmonized as EN 55025:2008 (not modified)

## Annex ZA (normative)

### Normative references to international publications with their corresponding European publications

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE 1 Where an International Publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

NOTE 2 Up-to-date information on the latest versions of the European Standards listed in this annex is available here: [www.cenelec.eu](http://www.cenelec.eu).

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
CISPR 16-1-1	-	Specification for radio disturbance and immunity measuring apparatus and Methods - Part 1-1: Radio disturbance and immunity measuring apparatus - Measuring apparatus	EN 55016-1-1	-



IEC 61967-1

Edition 2.0 2018-12

# INTERNATIONAL STANDARD

# NORME INTERNATIONALE

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**Integrated circuits – Measurement of electromagnetic emissions –  
Part 1: General conditions and definitions**

**Circuits intégrés – Mesure des émissions électromagnétiques –  
Partie 1: Conditions générales et définitions**





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IEC 61967-1

Edition 2.0 2018-12

# INTERNATIONAL STANDARD

# NORME INTERNATIONALE

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**Integrated circuits – Measurement of electromagnetic emissions –  
Part 1: General conditions and definitions**

**Circuits intégrés – Mesure des émissions électromagnétiques –  
Partie 1: Conditions générales et définitions**

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ICS 31.200

ISBN 978-2-8322-6284-9

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# INTERNATIONAL ELECTROTECHNICAL COMMISSION

## **INTEGRATED CIRCUITS – MEASUREMENT OF ELECTROMAGNETIC EMISSIONS –**

### **Part 1: General conditions and definitions**

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International Standard IEC 61967-1 has been prepared by subcommittee 47A: Integrated circuits, of IEC technical committee 47: Semiconductor devices.

This second edition cancels and replaces the first edition published in 2002. This edition constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition:

- a) the frequency range of 150 kHz to 1 GHz has been deleted from the title;
- b) the frequency step above 1 GHz has been added to Table 1, Table 2 and to 5.4;
- c) Table A.1 has been divided into two tables, and IEC 61967-8 has been added to Table A.2 of Annex A;
- d) the general test board description has been moved to Annex D.

The text of this International Standard is based on the following documents:

FDIS	Report on voting
47A/1062/FDIS	47A/1066/RVD

Full information on the voting for the approval of this International Standard can be found in the report on voting indicated in the above table.

This document has been drafted in accordance with the ISO/IEC Directives, Part 2.

A list of all parts of the IEC 61967 series, under the general title *Integrated circuits – Measurement of electromagnetic emissions*, can be found on the IEC website.

Future standards in this series will carry the new general title as cited above. Titles of existing standards in this series will be updated at the time of the next edition.

The committee has decided that the contents of this document will remain unchanged until the stability date indicated on the IEC website under "<http://webstore.iec.ch>" in the data related to the specific document. At this date, the document will be

- reconfirmed,
- withdrawn,
- replaced by a revised edition, or
- amended.

# INTEGRATED CIRCUITS – MEASUREMENT OF ELECTROMAGNETIC EMISSIONS –

## Part 1: General conditions and definitions

### 1 Scope

This part of IEC 61967 provides general information and definitions on the measurement of conducted and radiated electromagnetic disturbances from integrated circuits. It also provides a description of measurement conditions, test equipment and set-up as well as the test procedures and content of the test reports. Test method comparison tables are included in Annex A to assist in selecting the appropriate measurement method(s).

The object of this document is to describe general conditions in order to establish a uniform testing environment and to obtain a quantitative measure of RF disturbances from integrated circuits (IC). Critical parameters that are expected to influence the test results are described. Deviations from this document are noted explicitly in the individual test report. The measurement results can be used for comparison or other purposes.

Measurement of the voltage and current of conducted RF emissions or radiated RF disturbances, coming from an integrated circuit under controlled conditions, yields information about the potential for RF disturbances in an application of the integrated circuit.

The applicable frequency range is described in each part of IEC 61967.

### 2 Normative references

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

CISPR 16-1-1, *Specification for radio disturbance and immunity measuring apparatus and Methods – Part 1-1: Radio disturbance and immunity measuring apparatus – Measuring apparatus*

**koniec náhľadu – text ďalej pokračuje v platenej verzii STN**